

L Number	Hits	Search Text	DB	Time stamp
1	3	((contact with probe) same (acceptable or defective)) and (analy\$6 with surface) and (contact with pad)) and (probe with imag\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:31
2	2	(((contact with probe) same (acceptable or defective)) and (analy\$6 with surface) and (contact with pad)) and (probe with imag\$3)) and (tolerance with range)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:33
3	2	(((contact with probe) same (acceptable or defective)) and (analy\$6 with surface) and (contact with pad)) and (probe with imag\$3)) and (tolerance with range)) and (cross-section\$3 or (cross with section\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:34
4	2	(702/.ccls. or 342/.ccls. or 356/.ccls. or 367/.ccls.) and ((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:52
5	1	((702/.ccls. or 342/.ccls. or 356/.ccls. or 367/.ccls.) and ((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)) and (imag\$3 with probe)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:52
	1	detect\$3 same (surface with shape) same (contact with pad) same (contact with probe) same (three-dimensional with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 10:46
	1	(detect\$3 same (surface with shape) same (contact with pad)) and ((contact with probe) same (three-dimensional with data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:32
	1	(detect\$3 same (surface with shape)) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:38
	31	(surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:44
	28	((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and (circuit with substrate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:47
	28	(((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and (circuit with substrate)) and cross-section	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:40
	1	(((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and (circuit with substrate)) and cross-section) and curvature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:41

	1	((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and (circuit with substrate)) and cross-section) and (end near2 shape)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:42
	1	((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and ((surface with shape) same imag\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:44
	30	((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and imag\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:44
	1	((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and imag\$3) and ((contact with probe) same (acceptable or defective))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:45
	1	((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad) and (three-dimensional with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:46
	49	((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:37
	1	((((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)) and (circuit with substrate)) and (analy\$4 with surface with shape) and imag\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:48
	1	((((surface with shape) and (contact with pad) and (contact with probe) and (((three adj dimensional) or three-dimensional or 3D) with data)) and (circuit with substrate)) and cross-section) and (analy\$4 with surface with shape) and imag\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:48
	1	((((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)) and (circuit with substrate)) and ((surface with shape) same imag\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 18:49
	21	((((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)) and (circuit with substrate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 11:34
	1	(probe with test\$3) and (predetermin\$6 with dimension) and (detect\$3 with impression)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 10:48
	8	324/.ccls. and (((contact with probe) same (acceptable or defective)) and (surface with shape) and (contact with pad)) and (circuit with substrate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 11:17

	4	((contact with probe) same (acceptable or defective)) and (analy\$6 with surface) and (contact with pad)) and (circuit with substrate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 12:16
	4	((contact with probe) same (acceptable or defective)) and (analy\$6 with surface) and (contact with pad)) and (imag\$3 same surface)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/16 14:30